

The invention relates to oxide semiconductor equipment and technology, in particular to *n*-butanol sensors based on ZnO-Al<sub>2</sub>O<sub>3</sub> heterojunction.

The *n*-butanol sensor based on ZnO-Al<sub>2</sub>O<sub>3</sub> heterojunction comprises a glass substrate (1), on the surface of which by the chemical synthesis method from a solution is deposited a ZnO film (2), and on its surface by vacuum thermal evaporation of Al [Al(C<sub>3</sub>H<sub>7</sub>O)<sub>3</sub>] triisopropylate at the substrate temperature (1) equal to 450°C is deposited the Al<sub>2</sub>O<sub>3</sub> film (3) with a thickness of 17-20 nm, on the surface of which meander-shaped contacts of Au-Cr (4) are deposited and processed by fast photon annealing at T=650°C, t=30 s.

Claims: 1

Fig.: 3

